SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017
ANSI/NCSL Z540-1-1994

MICRON INSPECTION & CALIBRATION SERVICES
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CALIBRATION

Valid To: November 30, 2025 Certificate Number: 2917.01

In recognition of the successful completion of the A2LA evaluation process, accreditation is granted to this laboratory to perform the following calibrations[1, 10]:

I. Dimensional

Parameter/Equipment	Range	CMC[2, 4] (±)	Comments
Gage Blocks	Up to 4 in (5 to 20) in	(3 + 1.9*L*) µin (1.3 + 2.6*L*) µin	Master gage blocks
Calipers[3]	Up to 36 in	(580 + 2.5*L*) µin	Gage blocks, ring gauge
Micrometers[3]	Up to 24 in	(86 + 3.3*L*) µin	Gage blocks
Height Gage[3]	Up to 24 in	(30 + 1.9*L*) µin	Gage blocks, surface plate
Length Indicators[3] (Digital, Dial, Test, LVDTs)	Up to 0.010 in Up to 1 in	11 µin 37 µin	Universal measuring machine (UMM), gauge blocks, indicator calibrator
Cylindrical Gages – Plain Rings	Up to 6 in (6 to 12) in	(9 + 1*L*) µin (22 + 1.7*L*) µin	Universal measuring machine (UMM), cylindrical Rings

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Parameter/Equipment	Range	CMC[2, 4] (±)	Comments
Cylindrical Gages – Plain Plugs and Pins[3, 8]	Up to 12 in	(2.6 + 0.9*L*) µin	Universal measuring machine (UMM)
Thread Plugs –			
Simple Pitch Diameter	Up to 6 in	(63 + 0.8*L*) µin	Universal measuring machine (UMM) and thread wires
Major Diameter	Up to 6 in	(11 + 1.8*L*) µin	Universal measuring machine
Thread Rings –			
Solid Rings			Universal measuring machine (UMM) and thread balls.
Simple Pitch Diameter	Up to 2 in	(79 + 28*L*) µin	
Minor Diameter	Up to 2 in	(80 + 3.4*L*) µin	
Adjustable			Thread setting plug vision system
Simple Pitch Diameter	Up to 2 in	Class X Tolerance	
Minor Diameter	Up to 2 in	(80 + 3.4*L*) µin	
Optical Comparator[3] –			
Linearity	Up to 12 in	(127 + 7.1*L*) µin	Glass scale standard
Length Standard	Up to 40 in	(21 + 1.9*L*) µin	P&W 1000A ULM, gauge blocks length measuring system
Surface Finish Analyzer[3]	Ra: (16.1 to 119.5) µin	4 µin	Surface finish standards
Surface Finish Patch[3]	Ra: (16.1 to 119.5) µin	6 µin	Mitutoyo surface finish tester
Dial Indicator Calibrator	Up to 1 in	39 µin	Gage block and electronic amplifier

Parameter/Equipment	Range	CMC[2, 4] (±)	Comments
Thread Wires	Up to 0.5 in	8 µin	Universal measuring machine (UMM), gage blocks
Universal Measuring Machines (UMMs)	Up to 40 in	(6 + 8*L*) µin	Gage blocks, master plug gages, force gage
Optical Scales (Reticles, Optical Micrometer Scales, Optical Grids)	Up to 12 in	(67 + 8.6*L*) µin	OGP vision systems, glass scales/grids

II. Dimensional Testing/Calibration[6]

Parameter/Equipment	Range	CMC[2] (±)	Comments
Length, Angle, Geometry – Piece Parts, First Articles, Fixture Gages	3D Measurement: Up to 27.6 in	240 µin	CMM used for 3D measurements
Length, Angle, Geometry – Piece Parts, First Articles, Fixture Gages	Up to 16 in	140 µin	Vision systems used for measurements

III. Electrical – DC/Low Frequency

Parameter/Equipment	Range	CMC[2, 7] (±)	Comments
DC Voltage – Generate[3]	(0 to 330) mV (0.33 to 3.3) V (3.3 to 33) V (33 to 330) V (330 to 1020) V	15 µV/V + 1 µV 8.8 µV/V + 2 µV 9.4 µV/V + 20 µV 14 µV/V + 150 µV 14 µV/V + 1500 µV	Fluke 5522

Parameter/Equipment	Range	CMC[2, 7] (±)	Comments
DC Current – Generate[3]	(0 to 330) µA (0.33 to 3.3) mA (3.3 to 33) mA (33 to 330) mA (0.33 to 3) A (3 to 20.5) A	81 µA/A + 0.016 µA 58 µA/A + 0.039 µA 61 µA/A + 0.19 µA 61 µA/A + 1.9 µA 230 µA/A + 31 µA 620 µA/A + 580 µA	Fluke 5522
DC Voltage – Measure[3]	(0 to 200) mV (0.2 to 2) V (2 to 20) V (20 to 200) V (200 to 1000) V	6.1 µV/V + 0.13 µV 3.5 µV/V + 0.82 µV 3.5 µV/V + 7.5 µV 5.3 µV/V + 69 µV 5.6 µV/V + 0.67 mV	Fluke 8508A
DC Current – Measure[3]	(0 to 200) µA (0.2 to 2) mA (2 to 20) mA (20 to 200) mA (0.2 to 2) A (2 to 20) A	12 µA/A + 0.55 nA 13 µA/A + 4.3 nA 13 µA/A + 45 nA 40 µA/A + 1.4 µA 170 µA/A + 19 µA 360 µA/A + 0.63 mA	Fluke 8508A
Resistance – Generate[3]	(0 to 11) Ω (11 to 33) Ω (33 to 110) Ω (110 to 330) Ω (0.33 to 1.1) kΩ (1.1 to 3.3) kΩ (3.3 to 11) kΩ (11 to 33) kΩ (33 to 110) kΩ (110 to 330) kΩ (0.33 to 1.1) MΩ (1.1 to 3.3) MΩ (3.3 to 11) MΩ (11 to 33) MΩ (33 to 110) MΩ (110 to 330) MΩ (0.33 to 1.1) GΩ	73 µOhm/Ohm + 0.001 Ohm 30 µOhm/Ohm + 0.0015 Ohm 24 µOhm/Ohm + 0.0014 Ohm 27 µOhm/Ohm + 0.002 Ohm 22 µOhm/Ohm + 0.000 002 kOhm 0.0027 µOhm/Ohm + 0.000 02 kOhm 22 µOhm/Ohm + 0.000 02 kOhm 27 µOhm/Ohm + 0.0002 kOhm 22 µOhm/Ohm + 0.0002 kOhm 30 µOhm/Ohm + 0.002 kOhm 26 µOhm/Ohm + 0.000 002 MOhm 63 µOhm/Ohm + 0.000 03 MOhm 110 µOhm/Ohm + 0.000 05 MOhm 280 µOhm/Ohm + 0.0025 MOhm 0.047 µOhm/Ohm + 0.003 MOhm 0.24 % + 0.1 MOhm 1.1 % + 0.5 MOhm	Fluke 5522

Parameter/Equipment	Range	CMC[2, 7] (±)	Comments
Resistance – Measure[3]	(0 to 2) Ω (2 to 20) Ω (20 to 200) Ω (0.2 to 2) kΩ (2 to 20) kΩ (20 to 200) kΩ (0.2 to 2) MΩ (2 to 20) MΩ (20 to 200) MΩ (0.2 to 2) GΩ	16 μΩ/Ω + 5.2 μΩ 9 μΩ/Ω + 21 μΩ 7.6 μΩ/Ω + 70 μΩ 7.9 μΩ/Ω + 0.65 mΩ 7.2 μΩ/Ω + 14 mΩ 8.2 μΩ/Ω + 57 mΩ 13 μΩ/Ω + 1.6 Ω 22 μΩ/Ω + 0.10 kΩ 150 μΩ/Ω + 9.8 kΩ 0.14 % + 0.95 MΩ	Fluke 8508A

Parameter/Range	Frequency	CMC[2, 7] (±)	Comments
AC Voltage – Measure[3]			
(0 to 199) mV	(1 to 10) Hz (10 to 40) Hz (40 to 100) Hz (0.1 to 2) kHz (2 to 10) kHz (10 to 30) kHz (30 to 100) kHz	130 μV/V + 16 μV 130 μV/V + 5 μV 110 μV/V + 5 μV 110 μV/V + 2.4 μV 130 μV/V + 5 μV 420 μV/V + 10 μV 670 μV/V + 24 μV	Fluke 8508A
199 mV to 1.99 V	(1 to 10) Hz (10 to 40) Hz (40 to 100) Hz (0.1 to 2) kHz (2 to 10) kHz (10 to 30) kHz (30 to 100) kHz (0.1 to 1) MHz	120 μV/V + 0.14 mV 100 μV/V + 24 μV 84 μV/V + 24 μV 75 μV/V + 24 μV 120 μV/V + 24 μV 390 μV/V + 50 μV 540 μV/V + 0.24 mV 0.24 % + 24 mV	
(2 to 19.9) V	(1 to 10) Hz (10 to 40) Hz (40 to 100) Hz (0.1 to 2) kHz (2 to 10) kHz (10 to 30) kHz (30 to 100) kHz (0.1 to 1) MHz	120 μV/V + 1.4 mV 110 μV/V + 0.24 mV 84 μV/V + 0.24 mV 76 μV/V + 0.24 mV 130 μV/V + 0.24 mV 210 μV/V + 0.50 mV 460 μV/V + 2.4 mV 0.82 % + 0.24 V	

Parameter/Range	Frequency	CMC[2, 7] (±)	Comments
AC Voltage – Measure[3] (cont)			
(20 to 199) V	(1 to 10) Hz (10 to 40) Hz (40 to 100) Hz (0.1 to 2) kHz (2 to 10) kHz (10 to 30) kHz (30 to 100) kHz	120 µV/V + 14 mV 110 µV/V + 2.4 mV 91 µV/V + 2.4 mV 78 µV/V + 2.4 mV 120 µV/V + 2.4 mV 200 µV/V + 5.0 mV 480 µV/V + 24 mV	Fluke 8508A
(200 to 1000) V	(1 to 10) Hz (10 to 40) Hz (0.04 to 10) kHz (10 to 30) kHz (30 to 100) kHz	57 µV/V + 0.16 V 91 µV/V + 50 mV 93 µV/V + 50 mV 150 µV/V + 0.10 V 240 µV/V + 0.50 V	
AC Current – Measure[3]			
(0 to 200) µA	(1 to 10) Hz (0.01 to 10) kHz (10 to 30) kHz	260 µA/A + 24 nA 240 µA/A + 24 nA 430 µA/A + 24 nA	Fluke 8508A
200 µA to 2 mA	(1 to 10) Hz (0.01 to 10) kHz (10 to 30) kHz	270 µA/A + 0.24 µA 240 µA/A + 0.24 µA 340 µA/A + 0.24 µA	
(2 to 20) mA	(1 to 10) Hz (0.01 to 10) kHz (10 to 30) kHz	280 µA/A + 2.4 µA 250 µA/A + 2.4 µA 240 µA/A + 2.4 µA	
(20 to 200) mA	(1 to 10) Hz (0.01 to 10) kHz (10 to 30) kHz	280 µA/A + 24 µA 230 µA/A + 24 µA 240 µA/A + 24 µA	
200 mA to 2 A	(1 to 10) Hz (0.01 to 10) kHz (10 to 30) kHz	530 µA/A + 0.24 mA 520 µA/A + 0.24 mA 670 µA/A + 0.24 mA	
(2 to 20) A	(0.01 to 2) kHz (2 to 10) kHz	690 µA/A + 2.4 mA 0.21 % + 2.4 mA	

Parameter/Range	Frequency	CMC[2, 7] (±)	Comments
AC Current – Generate[3]			
(29 to 330) µA	(10 to 20) Hz (20 to 45) Hz (0.045 to 1) kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz	0.15 % + 0.1 µA 0.11 % + 0.1 µA 0.091 % + 0.1 µA 0.22 % + 0.15 µA 0.61 % + 0.2 µA 1.2 % + 0.4 µA	Fluke 5522
330 µA to 3.3 mA	(10 to 20) Hz (20 to 45) Hz (0.045 to 1) kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz	0.15 % + 0.000 15 mA 0.096 % + 0.000 15 mA 0.078 % + 0.000 15 mA 0.16 % + 0.0002 mA 0.39 % + 0.0003 mA 0.77 % + 0.0006 mA	
(3.3 to 33) mA	(10 to 20) Hz (20 to 45) Hz (0.045 to 1) kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz	0.14 % + 0.002 mA 0.07 % + 0.002 mA 0.03 % + 0.002 mA 0.061 % + 0.002 mA 0.15 % + 0.003 mA 0.32 % + 0.004 mA	
(33 to 330) mA	(10 to 20) Hz (20 to 45) Hz (0.045 to 1) kHz (1 to 5) kHz (5 to 10) kHz (10 to 30) kHz	0.14 % + 0.02 mA 0.07 % + 0.02 mA 0.03 % + 0.02 mA 0.058 % + 0.05 mA 0.15 % + 0.1 mA 0.3 % + 0.2 mA	
330 mA to 3 A	(10 to 45) Hz (0.045 to 1) kHz (1 to 5) kHz (5 to 10) kHz	0.14 % + 0.0001 A 0.047 % + 0.0001 A 0.47 % + 0.001 A 1.9 % + 0.005 A	
(3 to 20.5) A	(45 to 100) Hz (0.1 to 1) kHz (1 to 5) kHz	0.09 % + 0.005 A 0.11 % + 0.005 A 2.3 % + 0.005 A	
AC Voltage – Generate[3]			
Up to 33 mV	(10 to 45) Hz (0.045 to 10) kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz	400 µV/V + 6 µV 23 µV/V + 6 µV 53 µV/V + 6 µV 530 µV/V + 6 µV 0.2 % + 0.012 mV 0.43 % + 0.05 mV	Fluke 5522

Parameter/Range	Frequency	CMC[2, 7] (±)	Comments
AC Voltage – Generate (cont)[3]			
(33 to 330) mV	(10 to 45) Hz (0.045 to 10) kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz	230 µV/V + 8 µV 110 µV/V + 8 µV 130 µV/V + 8 µV 270 µV/V + 8 µV 590 µV/V + 32 µV 0.15 % + 0.07 mV	Fluke 5522
330 mV to 3.3 V	(10 to 45) Hz (0.045 to 10) kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz (100 to 500) kHz	230 µV/V + 50 µV 110 µV/V + 60 µV 140 µV/V + 60 µV 230 µV/V + 50 µV 530 µV/V + 130 µV 0.18 % + 0.0006 V	
(3.3 to 33) V	(10 to 45) Hz (0.045 to 10) kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz	230 µV/V + 650 µV 110 µV/V + 600 µV 180 µV/V + 600 µV 270 µV/V + 600 µV 680 µV/V + 1600 µV	
(33 to 330) V	(10 to 45) Hz (0.045 to 10) kHz (10 to 20) kHz (20 to 50) kHz (50 to 100) kHz	150 µV/V + 2 mV 150 µV/V + 6 mV 190 µV/V + 6 mV 230 µV/V + 6 mV 0.15 % + 0.05 V	
(330 to 1020) V	(10 to 45) Hz (0.045 to 1) kHz (1 to 5) kHz (5 to 10) kHz	230 µV/V + 10 mV 190 µV/V + 10 mV 190 µV/V + 10 mV 230 µV/V + 10 mV	

Parameter/Range	Frequency	CMC[2, 7] (±)	Comments
Capacitance – Generate[3]			
0.35 nF	10 Hz to 10 kHz	0.4 % + 7.8 pF	Fluke 5522
1.1 nF	10 Hz to 10 kHz	0.3 % + 0.01 nF	
3.3 nF	10 Hz to 3 kHz	0.43 % + 0.01 nF	
11 nF	10 Hz to 1 kHz	0.21 % + 0.01 nF	
33 nF	10 Hz to 1 kHz	0.13 % + 0.1 nF	
109 nF	10 Hz to 1 kHz	0.18 % + 0.1 nF	
300 nF	10 Hz to 1 kHz	0.18 % + 0.3 nF	
1.09 µF	(10 to 600) Hz	0.18 % + 0.001 uF	
3 µF	(10 to 300) Hz	0.18 % + 0.003 uF	
10.9 µF	(10 to 150) Hz	0.18 % + 0.01 uF	
30 µF	(10 to 120) Hz	0.3 % + 0.03 uF	
109 µF	(10 to 80) Hz	0.36 % + 0.1 uF	
300 µF	(0 to 50) Hz	0.33 % + 0.3 uF	
1.09 mF	(0 to 20) Hz	0.35 % + 0.001 mF	
3 mF	(0 to 6) Hz	0.33 % + 0.003 mF	
10.9 mF	(0 to 2) Hz	0.35 % + 0.01 mF	
30 mF	(0 to 0.6) Hz	0.57 % + 0.03 mF	
109 mF	(0 to 0.2) Hz	0.82 % + 0.1 mF	

Parameter/Equipment	Range	CMC[2, 9] (±)	Comments
Electrical Simulation of Thermocouples – Generate			
Type E	(-250 to -100) °C	0.42 °C	Fluke 5522
	(-100 to -25) °C	0.21 °C	
	(-25 to 350) °C	0.20 °C	
	(350 to 650) °C	0.21 °C	
	(650 to 1000) °C	0.23 °C	

Parameter/Equipment	Range	CMC[2, 9] (±)	Comments
Electrical Simulation of Thermocouples – Generate (cont)			
Type J	(-210 to -100) °C (-100 to -30) °C (-30 to 150) °C (150 to 760) °C (760 to 1200) °C	0.26 °C 0.19 °C 0.18 °C 0.19 °C 0.23 °C	Fluke 5522
Type K	(-200 to -100) °C (-100 to -25) °C (-25 to 120) °C (120 to 1000) °C (1000 to 1372) °C	0.29 °C 0.20 °C 0.19 °C 0.24 °C 0.34 °C	
Type R	(0 to 250) °C (250 to 400) °C (400 to 1000) °C (1000 to 1767) °C	0.47 °C 0.32 °C 0.31 °C 0.35 °C	
Type S	(0 to 250) °C (250 to 400) °C (400 to 1400) °C (1400 to 1767) °C	0.40 °C 0.33 °C 0.33 °C 0.39 °C	
Type T	(-250 to -150) °C (-150 to 0) °C (0 to 120) °C (120 to 400) °C	0.51 °C 0.23 °C 0.19 °C 0.18 °C	
Type U	(-200 to 0) °C (0 to 600) °C	0.46 °C 0.25 °C	

IV. Mechanical

Parameter/Equipment	Range	CMC[2, 4, 5, 9] (±)	Comments
Scales and Balances[3]	(0 to 300) lb	0.04 lb	Using NIST Class F weights
	(1 to 10) g (10 to 50) g (50 to 200) g (200 to 1000) g	0.21 mg 0.21 mg 0.052 mg + 0.011 mg/g 0.012 mg + 0.06 mg/g	Using ASTM Class 1 weights
Gas Pressure (Absolute) – Measuring Devices	(1.5 to 7) psia (>7 to 15) psia (>15 to 30) psia	0.003 psia 0.003 psia 0.004 psia	Fluke PM600-A200K pressure transducer
	(5 to 100) psia (>100 to 200) psia	0.01 psia 0.03 psia	Fluke PM600-A1.4M pressure transducer
	(14.5 to 50) psia (50 to 250) psia (250 to 500) psia (500 to 1000) psia	0.01 psia 0.03 psia 0.05 psia 0.11 psia	Fluke PM600-A7M pressure transducer
Hydraulic Gauge Pressure[3] – Measuring Devices and Gauges	(10 to 2000) psi (2000 to 4000) psi (4000 to 6000) psi (6000 to 8000) psi (8000 to 10 000) psi	0.39 psi + 0.6*R* 0.77 psi + 0.6*R* 1.2 psi + 0.6*R* 1.6 psi + 0.6*R* 2.0 psi + 0.6*R*	Fluke P3124-PSI deadweight tester
Gas Gauge Pressure – Measuring Devices and Gauges	(-13 to 10) psi (10 to 36) psi (36 to 360) psi	0.12 psi + 0.6*R* 0.15 psi + 0.6*R* 0.16 psi + 0.6*R*	Additel ADT761-M pressure calibrator
Torque Transducers	(5 to 200) ozf·in (5 to 400) lbf·in (40 to 1000) lbf·in (25 to 600) lbf·ft (60 to 2000) lbf·ft	0.09 % IV + 0.58*R* 0.10 % IV + 0.58*R* 0.13 % IV + 0.58*R* 0.14 % IV + 0.58*R* 0.09 % IV + 0.58*R*	Using CI torque arms and NIST Class F weights

Parameter/Equipment	Range	CMC[2, 4, 5] (±)	Comments
Torque Gages[3]	(5 to 50) ozf·in (50 to 200) ozf·in (30 to 400) lbf·in (400 to 1000) lbf·in (30 to 50) lbf·ft (50 to 250) lbf·ft (250 to 600) lbf·ft (100 to 1000) lbf·ft	0.78 % IV + 0.6*R* 0.42 % IV + 0.6*R* 0.54 % IV + 0.6*R* 0.61 % IV + 0.6*R* 0.43 % IV + 0.6*R* 0.36 % IV + 0.6*R* 0.48 % IV + 0.6*R* 0.43 % IV + 0.6*R*	Torque transducers

VI. Thermodynamics

Parameter/Equipment	Range	CMC[2, 4, 9] (±)	Comments
Temperature[3] – Measuring Equipment (Digital and Mechanical)	(-45 to 500) °C	0.12 °C	Fluke 2560 readout and Fluke 5628 PRT probe, liquid bath, dry well
Temperature[3] – Measure (Chambers, Ovens, Freezers)	(0 to 20) °C	0.30 °C	Vaisala M170 temperature probe with readout
Relative Humidity – Measuring Devices[3]	(25 to 75) % RH	1.0 % RH + 0.6*R*	Vaisala HMP75 humidity probe with readout and humidity chamber
Relative Humidity – Measure[3] (Humidity Chambers)	(25 to 75) % RH	1.6 % RH + 0.6*R*	Vaisala HMP75 humidity probe with readout

[1] This laboratory offers commercial dimensional testing, calibration and field services where noted.

[2] Calibration and Measurement Capability Uncertainty (CMC) is the smallest uncertainty of measurement that a laboratory can achieve within its scope of accreditation when performing more or less routine calibrations of nearly ideal measurement standards of nearly ideal measuring equipment. CMCs represent expanded uncertainties expressed at approximately the 95 % level of confidence, usually using a coverage factor of $k = 2$. The actual measurement uncertainty of a specific calibration performed by the laboratory may be greater than the CMC due to the behavior of the customer's device and to influences from the circumstances of the specific calibration.

[3] Field calibration service is available for this calibration. Please note the actual measurement uncertainties achievable at customer's site can normally be expected to be larger than the CMC uncertainty found on the A2LA Scope. Allowance must be made for aspects such as the environment at the place of calibration and for other possible adverse effects such as those caused by transportation of the calibration equipment. The usual allowance for the uncertainty introduced by the item being calibrated, (e.g., resolution) must also be considered and this, on its own, could result in the actual measurement uncertainty achievable on a customer's site being larger than the CMC.

[4] In the statement of CMC, *L* is the numerical value of the nominal length of the device measured in inches. In the statement of CMC, div is the lowest division identified for the resolution of the unit under calibration. In the statement of CMC, *R* is the resolution of the unit under test.

[5] In the statement of CMC, percentages are to be read as percent of reading, unless noted otherwise. In the statement of CMC, percent IV is to be read as percent of indicated value.

[6] This laboratory meets R205 – *Specific Requirements: Calibration Laboratory Accreditation Program* for the types of dimensional tests listed above and is considered equivalent to that of a calibration.

[7] The stated measured values are determined using the indicated instrument (see Comments). This capability is suitable for the calibration of the devices intended to measure or generate the measured value in the ranges indicated. CMCs are expressed as either a specific value that covers the full range or as a percent or fraction of the reading plus a fixed floor specification.

[8] Field calibrations limited to pin gages and a range of 0.75 inches.

[9] The type of instrument or material being calibrated is defined by the parameter. This indicates the laboratory is capable of calibrating instruments that measure or generate the values in the ranges indicated for the listed measurement parameter.

[10] This scope meets A2LA's *P112 Flexible Scope Policy.*

Accredited Laboratory

A2LA has accredited

MICRON INSPECTION & CALIBRATION SERVICES

York, PA

for technical competence in the field of

Calibration

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017 *General requirements for the competence of testing and calibration laboratories*. This laboratory also meets the requirements of ANSI/NCSL Z540-1-1994 and R205 – Specific Requirements: Calibration Laboratory Accreditation Program. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (*refer to joint ISO-ILAC-IAF Communiqué dated April 2017*).

Presented this 14th day of December 2023.

Mr. Trace McInturff, Vice President, Accreditation Services
For the Accreditation Council
Certificate Number 2917.01
Valid to November 30, 2025

For the calibrations to which this accreditation applies, please refer to the laboratory's Calibration Scope of Accreditation.